

Notice of References Cited

Application/Control No.

10/726,882

Applicant(s)/Patent Under

Reexamination

ARIK ET AL.

Examiner

Jason M. Han

Art Unit

2875

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,481,874	11-2002	Petroski, James T.	362/373
B	US-5,008,582	04-1991	Tanuma et al.	310/332
C	US-4,501,319	02-1985	Edelman et al.	165/84
D	US-4,406,323	09-1983	Edelman, Seymour	165/84
E	US-6,588,497	07-2003	Glezer et al.	165/84
F	US-4,498,851	02-1985	Kolm et al.	417/410.2
G	US-4,595,338	06-1986	Kolm et al.	416/81
H	US-4,780,062	10-1988	Yamada et al.	417/410.2
I	US-4,923,000	05-1990	Nelson, Richard D.	165/122
J	US-5,861,703	01-1999	Losinski, Armand	310/330
K	US-5,921,757	07-1999	Tsutsui et al.	417/410.2
L	US-6,045,240	04-2000	Hochstein, Peter A.	362/294
M	US-6,517,221	02-2003	Xie, Bo Ping	362/373

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
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X	

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